

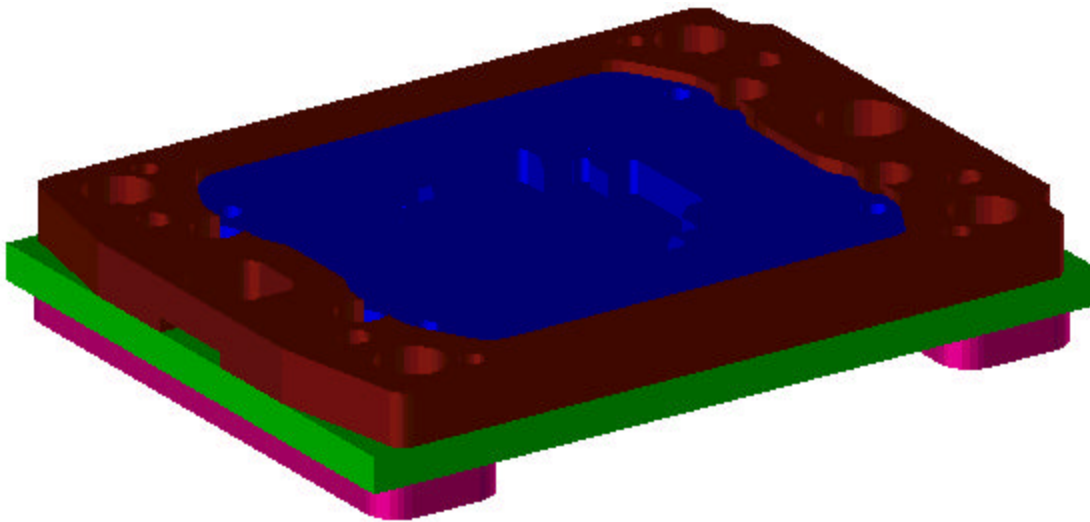
Li TEST SOCKET

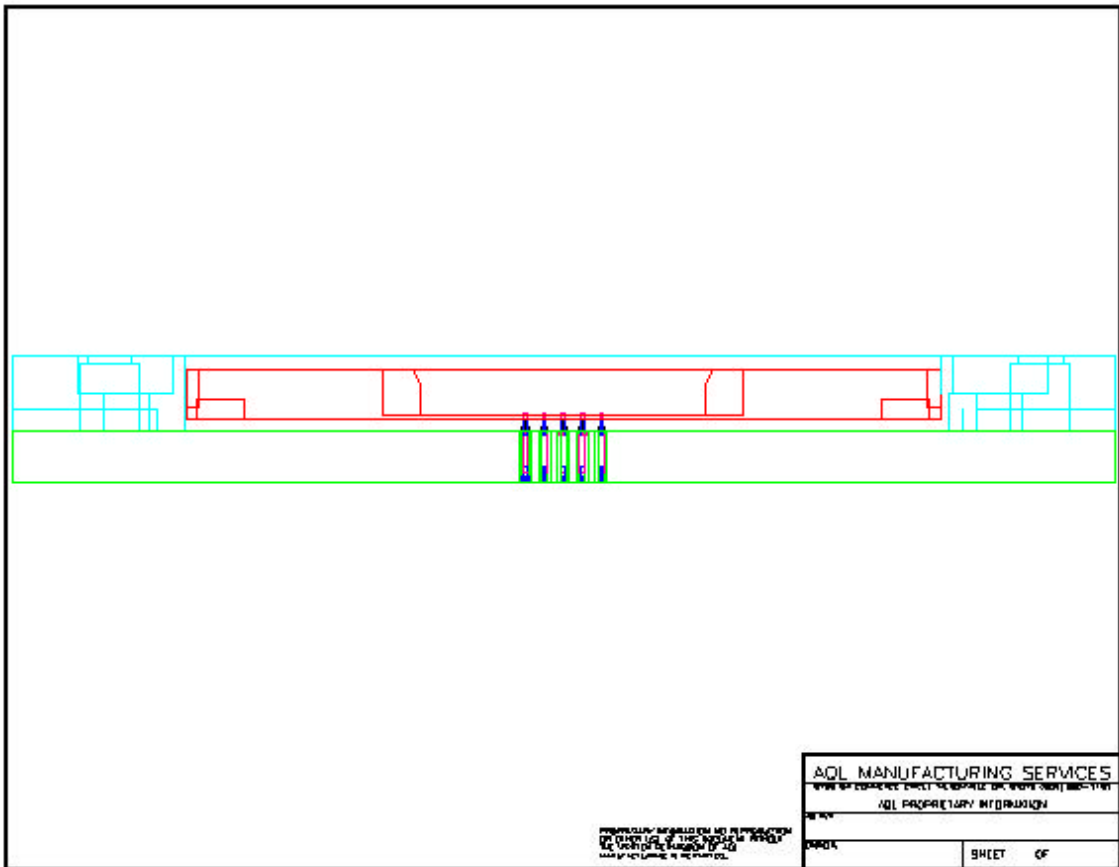
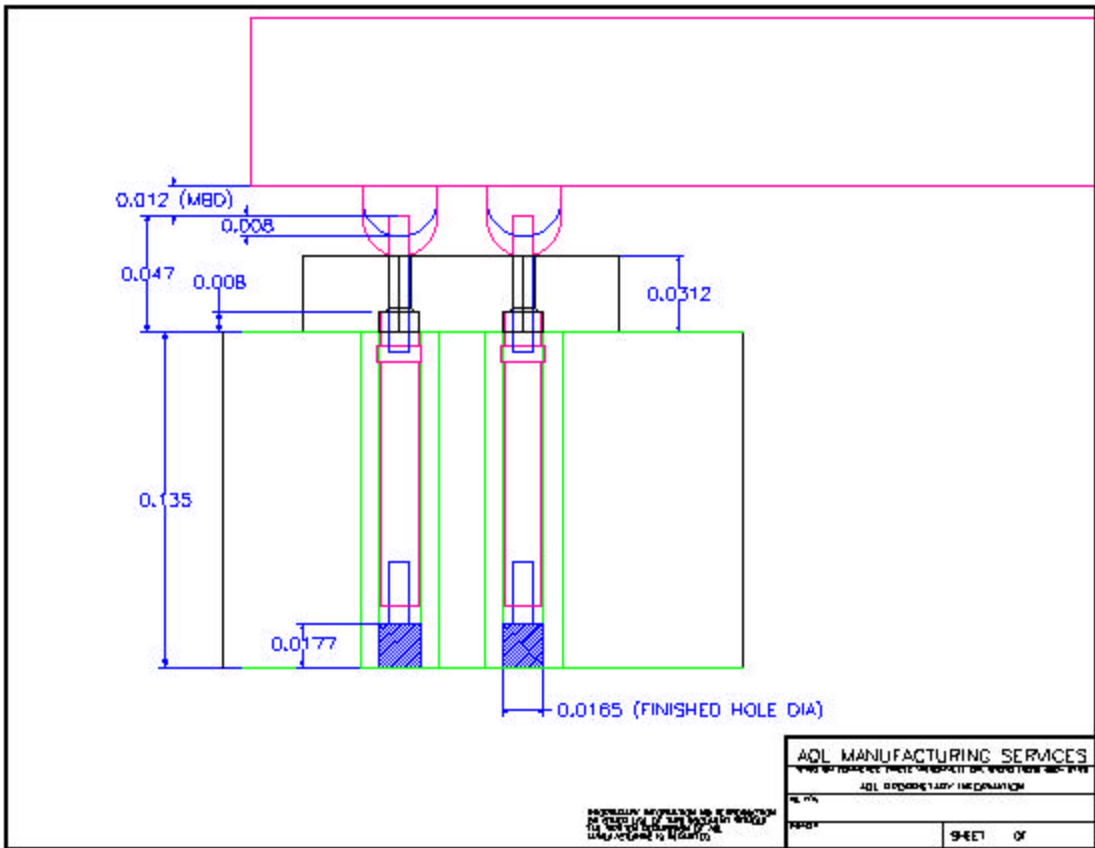
AQL is pleased to announce the new Li Test socket. The concept involves the physical attributes of the double-ended spring probe and the process of how they are interfaced with the DUT board.

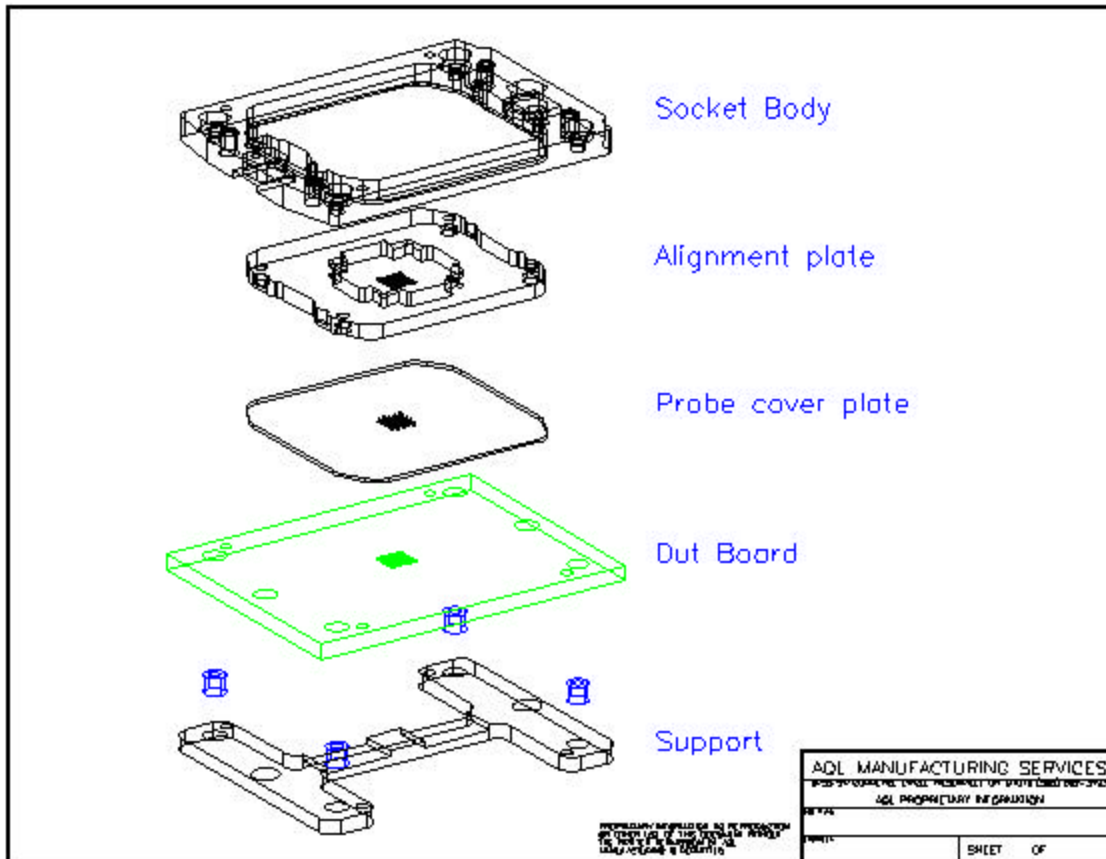
The spring probe has a compliant plunger, which allows each individual test point to address slight changes in ball heights and to provide a constant mechanical force. Though the probe can be compressed thousands of cycles, it has high inductance, partially caused by its physical length. Due to its unshielded height, it also causes cross talk with the adjacent signal probes.

Today's Test Engineers would like the test sockets to simulate the device as if it was soldered to the board. Inductance less than 1 Nano Henry is a preferred test criteria.

AQL's new Li test socket addresses the above listed physical problems by placing the spring probes inside the DUT board, not connected to the pad on the outside of the board. With the probes inside the board, it dramatically reduces the exposure of one signal probe to another and hence lowers the cross talk, along with other parasitic signals.







With our Li socket design, the device under test will be only .031" above the DUT board and the spring probe travel or its ability to compensate for height variation is .020". It still retains a mechanical force of 1oz per test point. This technology allows virtually any number of test points, but can only be used with pitches greater than 1.00mm.

AQL's preliminary testing shows that the inductance using this concept is under .5nH. Each test point can be individually replaced since it has a mechanical connection to the plated through hole, not soldered in the hole.

AQL's Li Test socket incorporates:

- An articulated Hand Actuator, which is removable for production testing
- A movable Alignment plate
- A backing plate.

Please contact AQL to discuss DUT board criteria to incorporate our Li socket in your next project.